Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/748,620	CHAN, LAI SHUN	
Examiner	Art Unit	

Steven J. Ganey

3752

SEARCHED					
Class	Subclass	Date	Examiner		
239	548,525, 530,602, 600,552				
	DIG19	9/19/05	Sa		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text and inventorship search.	વીલિંગ્ડ	502
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